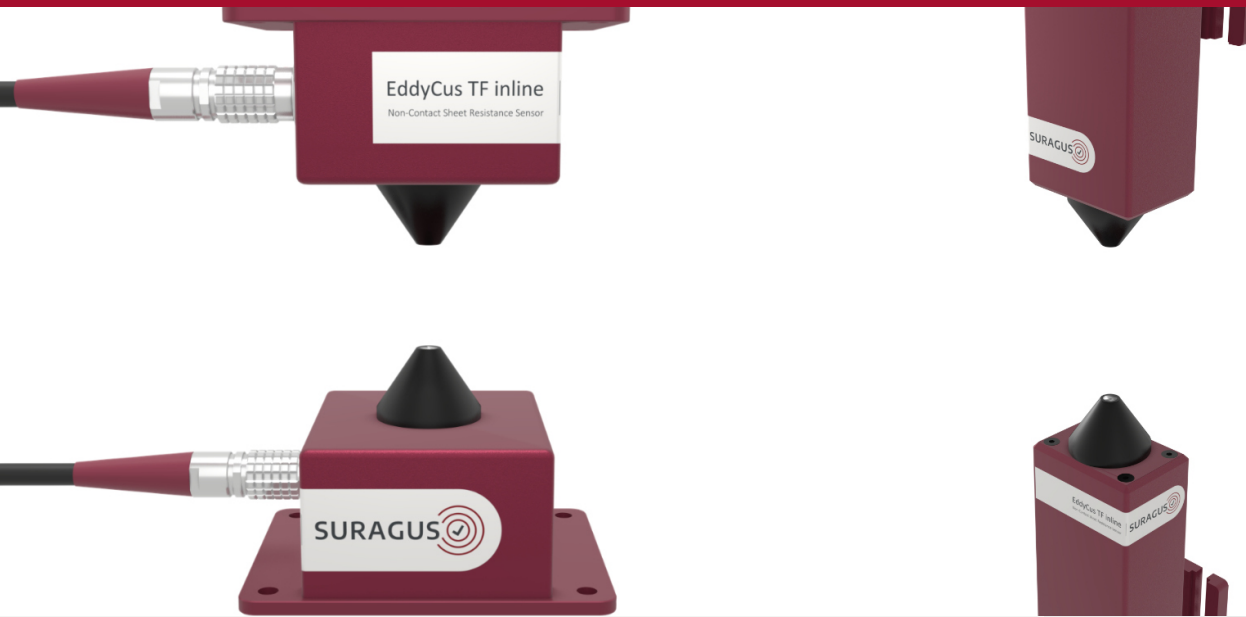


EddyCus[®] TF inline RM – Resistivity Monitoring

P_T_inlineRM_20



Highlights

- ▶ Contact-free and realtime
- ▶ Accurate measurement
- ▶ High degree of variability and flexibility
 - ▶ In- and ex-vacuo solutions
 - ▶ Fixed sensor and traverse solutions
 - ▶ Single-lane and multi-lane solutions
- ▶ High sample rate up to 1,000 measurements per second

Applications

- ▶ Wafer resistivity
- ▶ Ingot and boule resistivity
- ▶ Sputter target composition
- ▶ Purity assessment
- ▶ Electrical discharge machining
- ▶ Material sorting
- ▶ Melting, casting, sintering
- ▶ Defect imaging and integrity assessment

Parameters

- ▶ Sheet resistance (Ohm/sq)
- ▶ Metal layer thickness (nm, μm)
- ▶ Metal substrate thickness (μm)
- ▶ Anisotropy
- ▶ Defects
- ▶ Integrity assessment

Materials

- ▶ Semiconductors
 - ▶ Si, SiC, SiSiC
 - ▶ GaAs, GaN
- ▶ Alloys
- ▶ Metals
- ▶ Graphite
- ▶ Graphene
- ▶ Compounds
- ▶ Composites

SURAGUS GmbH
Maria-Reiche-Strasse 1
01109 Dresden
Germany

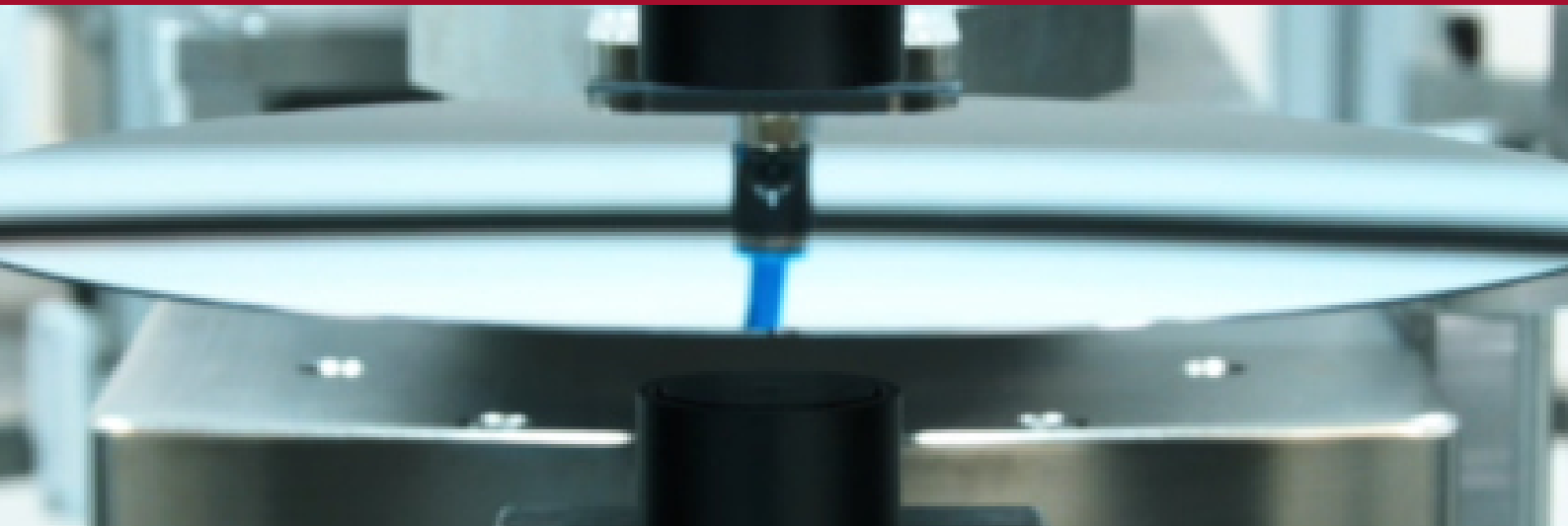
For further questions:
+49 351 32 111 520

sales@suragus.com

Visit us at:
www.suragus.com
www.suragus.com/calculator
www.suragus.com/EddyCusInline

Made and Engineered in Germany 





Sheet resistance measurement technology	Non-contact eddy current sensor
Substrates	e.g. foils, glass, wafer, etc.
Measurement gap size	5 / 10 / 15 / 25 / 50 / 75 mm
Number of sensor pairs / monitoring lanes	1 – 99
Sensor sizes (W x L x H) in mm	Sensor M: 80 x 100 x 66 Sensor S: 34 x 48 x 117
Conductive layers	Metals/ TCOs/ CNTs/ nanowires/ graphene/ grids/ PEDOT/ others
Resistivity range	0.1 mOhm·cm – 5 Ohm·cm
Conductivity range	0.01 – 65 MS/m
Other integrated measurements	Metal thickness/ optical transmittance/ density/ anisotropy
Environment	Ex-vacuo/ in-vacuo @ T < 60°C / 140°F (higher upon request)
Sample rate	1 / 10 / 50 / 100 / 1,000 measurements per second
Hardware trigger	5 / 12 / 24 V
Interfaces	UDP, .Net libraries, TCP, Modbus, analog/digital

Device Control and Software

- ▶ Several views and user levels
- ▶ Live view with upper and lower limits and alarm functions
- ▶ Analysis view providing statistics
- ▶ Can handle data of several thousands measurements per second
- ▶ Data storage into SQL database
- ▶ Customizable automatic data export (csv, txt, xls,...)
- ▶ Several smart functions (automated DB cleaning, self-reference etc.)
- ▶ Parameterizable I/O modules (triggering of actions or alarms)

